Tektronix SuperSpeed Test Solution Supports World's First USB 3.0 Certification At NEC Electronics

Tektronix, Inc., the world's leading manufacturer of oscilloscopes, today announced that its SuperSpeed USB solution supported the verification of signal quality for NEC Electronics Corporation's USB 3.0-compatible host controller -the world's first to obtain USB 3.0 certification from the USB Implementers Forum.

NEC Electronics, a global leader in the design and production of integrated circuits, worked with Tektronix to validate that its new silicon components meet the requirements of the emerging SuperSpeed USB standard (USB3.0). USB technology has quickly become recognized as the industry standard for connecting PCs and peripheral devices. Comparable to other state-of-the-art high-speed interfaces such as PCI Express 2.0 and SATA Gen 3, the performance of USB 3.0, which can support a data rate of up to 5Gbps, can pose complicated measurement challenges. To resolve these challenges, measurement devices with high levels of performance and flexibility, as well as tools to speed and simplify the design, measurement, and analysis processes are required. The Tektronix Test Solution for USB 3.0 provides engineers like those at NEC Electronics with the capability to perform characterization, debug, and compliance testing of their USB devices and automates margin and compliance testing. For critical USB 3.0 receiver margin testing, the Tektronix AWG7122B arbitrary waveform generator provides unmatched signal generation flexibility - helping to bring USB 3.0-compatible products to market faster.

"Tektronix has been working closely with NEC Electronics on the verification, testing, and debugging of SuperSpeed USB," said Dave Slack, marketing manager, Technology Solutions Group, Tektronix, Inc. "Today, we are pleased to have contributed to the product development by NEC Electronics that led to the industry's first USB 3.0 certification."

Tektronix's USB 3.0 Solution

The Tektronix SuperSpeed USB compliance solution is built on a foundation of instruments -- real-time and sampling oscilloscopes, arbitrary waveform generators, and more -- that offer measurement performance that meets the demands of high speed serial protocols. The DSA71254B real-time oscilloscope, for example, provides a high-bandwidth, low-noise environment for accurate capture and analysis of fast serial signal clock rates. Having a well-matched oscilloscope acquisition system is critical to eye diagram analysis and margin testing for compliance. Similarly, the AWG7122B arbitrary waveform generator provides complex waveforms containing stresses that mimic the degrading effects of transmission paths to support receiver testing. These hardware tools are paired with

expert software applications such as the DPOJET Jitter and Eye Diagram Analysis Tool, SerialXpress Advanced Jitter Generation Tool, and TekExpress(tm) USB 3.0 Automated Compliance Test Software to provide designers the tools they need to verify and debug their designs.

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